Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/784,716	ISHIHARA ET AL.
Examiner	Art Unit
John O. Nauven	3654

	SEARCHED			
Class	Subclass	Date	Examiner	
242	338.1 343 348 348.2	9/28/2005	JN	
360	132	9/28/2005	JN	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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